

Abstract**LED testing process and correction methods therefor**

Disclosed is a method of generating a correction function for a light-emitting diode (LED) testing process. The method comprises the steps of: detecting light emitted by a reference LED and reflected from one or more inactive LEDs on a panel within a field of view of a detector, a number of said inactive LEDs within the field of view being varied such that uncorrected values of at least one optical parameter are derivable as a function of the number of inactive LEDs in the field of view; detecting light emitted by the reference LED, or by an active LED having identical optical properties to the reference LED, in the absence of any other LEDs, to determine at least one reference value for the or each said optical parameter; and calculating differences between the uncorrected values and the or each reference value to generate the correction function, the correction function being based on the number of inactive LEDs which are arranged within the field of view of the detector when the detector detects light emitted by an LED under test.

[FIG. 3]